Verification of Compliance

Product Name

PCIE-USB380,PCIE-USB340

Trade Name

Neousys Technology

Model Number

PCIE-USB380,PCIE-USB340

Applicant

: Neousys Technology

Address

: 15F, No.868-3, Zhongzheng Rd., Zhonghe Dist., New Taipei City

23586, Taiwan

Report Number

: O22-U070-1311-287

Issue Date

December 5, 2013

Applicable Standards: EN 55022:2010+AC:2011 Class B ITE

AS/NZS CISPR22:2009+A1:2010 Class B ITE

EN 61000-3-2: 2006+A1:2009+A2:2009

EN 61000-3-3:2008 EN 55024:2010 EN 61000-4-2:2009

EN 61000-4-3:2006+A1:2008+A2:2010

EN 61000-4-4:2012 EN 61000-4-5:2006 EN 61000-4-6:2009 EN 61000-4-8:2010 EN 61000-4-11:2004

Based on the EMC Directive 2004/108/EC and the specifications of the customer, one sample of the designated product has been tested in our laboratory and found to be in compliance with the EMC standards cited above.



TAF 0905 FCC CAB Code TW1053 NVLAP Lab Code 200575-0 IC Code 4699A

VCCI Accep. No. R-1527, C-1609, T-1441, G-10,

T-1334, G-10, G-614



Central Research Technology Co.

EMC Test Laboratory

11, Lane 41, Fushuen St., Jungshan Chiu, Taipei, Taiwan, 104, R.O.C.

Tel: 886-2-25984568

Fax: 886-2-25984546

(Tsun-Yu Shih/ General Manager)

Date: December 5, 2013

Declaration of Conformity

The following device: Product Name : PCIE-USB380.PCIE-USB340 Model No. : PCIE-USB380,PCIE-USB340 is here with confirmed to comply with the requirements set out in the Council Directive on the Approximation of the laws of the European Council EMC Directive 2004/108/EC. The characteristics of electromagnetic compatibility have been evaluated by Central Research Technology Co., and the results are shown in the test report. (Report No.: O22-U070-1311-287, issued in 2013), For the evaluation regarding the Directives, the following standards were applied: EN 55022:2010+AC:2011 Class B ITE EN 55024:2010 AS/NZS CISPR22:2009+A1:2010 Class B ITE EN 61000-4-2:2009 EN 61000-3-2:2006+A1:2009+A2:2009 EN 61000-4-3:2006+A1:2008+A2:2010 EN 61000-3-3:2008 EN 61000-4-4:2012 EN 61000-4-5:2006 EN 61000-4-6:2009 EN 61000-4-8:2010 EN 61000-4-11:2004 It is understood that each unit marketed is identical to the device as tested, and any changes to the device that could adversely affect the EMC characteristics will require retest. The following importer/manufacturer is responsible for this declaration: Company Name Company Address: (in E.U.) Telephone Fax: The person to be responsible for marking this declaration: Name (Full name) Position/Title

Date

Legal Signature

CE EMC Test Report

for

PCIE-USB380,PCIE-USB340

Brand Name : Neousys Technology

Model No. : PCIE-USB380,PCIE-USB340

Report Number : 022-U070-1311-287

Date of Receipt : November 26, 2013

Date of Report : December 5, 2013

Prepared for

Neousys Technology

15F, No.868-3, Zhongzheng Rd., Zhonghe Dist., New Taipei City 23586, Taiwan



Prepared by

Central Research Technology Co. EMC Test Laboratory

11, Lane 41, Fushuen St., Jungshan Chiu, Taipei, Taiwan, 104, R.O.C.

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Verification of Compliance

Equipment Under Test : PCIE-USB380,PCIE-USB340 Model No. : PCIE-USB380,PCIE-USB340

Applicant : Neousys Technology

Address : 15F, No.868-3, Zhongzheng Rd., Zhonghe Dist., New Taipei

City 23586, Taiwan

Applicable Standards : EN 55022:2010+AC:2011 Class B ITE

AS/NZS CISPR22:2009+A1:2010 Class B ITE

EN 61000-3-2:2006+A1:2009+A2:2009

EN 61000-3-3:2008 EN 55024:2010 EN 61000-4-2:2009

EN 61000-4-3:2006+A1:2008+A2:2010

EN 61000-4-4:2012 EN 61000-4-5:2006 EN 61000-4-6:2009 EN 61000-4-8:2010

EN 61000-4-11:2004

: November 27~29, 2013 **Date of Testing**

: The test method and configuration of EMS tests are following Deviation

the requirement of the applicable standards cited above.

: Engineering Sample **Condition of Test Sample**

We, Central Research Technology Co., hereby certify that one sample of the designated product was tested in our facility during the period mentioned above. The test records, data evaluation and Equipment Under Test (EUT) configurations shown in the present report are true and accurate representation of the measurements of the sample's EMC characteristics under the conditions herein specified.

The test results show that the EUT as described in the present report is in compliance with the requirements set forth in the standards mentioned above and apply to the tested sample identified in the present report only. The test report shall not be reproduced, except in its entirety, without the written approval of Central Research Technology Co.

: Lis Chen/System Executive) , DATE : PREPARED BY

APPROVED BY

(Tsun-Yu Shih/General Manager)

TEL.: 886-2-25984542 FAX.: 886-2-25984546 Page: 2 / 82

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1. General Description

1.1 General Description of EUT

Equipment Under Test : PCIE-USB380,PCIE-USB340

Model No. : PCIE-USB380,PCIE-USB340

Power in : Supplied by the connected PC

Highest Operating Frequency : 4.8GHz from the test specification

Manufacturer : Neousys Technology

Function Description :

The EUT is an engineering sample of the PCIE-USB380. Please refer to the user's

manual for the details.

The I/O ports of EUT are listed below:

No.	I/O Port Type	Quantity
1	PCIe connected port	1
2	USB 3.0 port	8

1.2 **Test Mode**

Normal operating as the specification of manufacturer.



1.3 Applied standards

According to the specifications of the manufacturer and the requirements set in European Council EMC Directive 2004/108/EC, the applied standards to evaluate the compliance of the EUT are as following:

Applied Standards	Test Items	Results
☑ EN 55022:2010+AC:2011 Class B ITE	Conducted Emission	PASS
☑ AS/NZS CISPR22:2009+A1:2010	Measurement	17.00
Class B ITE	Radiated Emission Measurement	<u>PASS</u>
☑ EN 61000-3-2:2006+A1:2009+A2:2009	Harmonic Current Emission Measurement	<u>PASS</u>
☑ EN 61000-3-3:2008	Voltage Fluctuation and Flicker Emission Measurement	<u>PASS</u>
☑ EN 55024:2010		
☑ EN 61000-4-2:2009	Electrostatic discharge Test (ESD)	<u>PASS</u>
☑ EN 61000-4-3:2006+A1:2008+A2:2010	Radiated electromagnetic field immunity Test (RS)	<u>PASS</u>
☑ EN 61000-4-4:2012	Electrical fast transient / burst immunity Test (EFT)	<u>PASS</u>
☑ EN 61000-4-5:2006	Surge immunity Test	<u>PASS</u>
☑ EN 61000-4-6:2009	Immunity to conducted disturbances, induced by radio-frequency fields (CS)	<u>PASS</u>
☑ EN 61000-4-8:2010	Power frequency magnetic field immunity Test (PFM)	<u>PASS</u>
☑ EN 61000-4-11:2004	Voltage dips, short interruptions Test	<u>PASS</u>

1.4 Test Setup for the EUT

The EUT is an unique unit connected with other necessary accessories and support units listed in the next section. It has been tested against each standard after the following setup steps:

- a. Install the EUT inside a PC.
- b. Connect all the necessary accessories and support units to the appropriate power source.
- c. Turn on the PC and all the accessories and support units.
- d. Load an EMC test software into the PC and execute it under the Windows environment.
- e. The PC reads/ writes messages from/ to the USB 3.0 HDD by the EUT continuously.
- f. The PC sends "H" patterns to the monitor continuously.
- g. The PC sends messages to the modem.
- h. The PC sends "H" patterns to the printer, which prints them on paper.
- i. Repeat and keep the setup steps listed above before and during all tests.

EUT I/O ports / Peripherals	Exerciser Program (software)	Version of Program
EUT		
Monitor		
Modem	BurnIn Test.exe	V 7.1
USB 3.0 HDD		
Printer		

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1.5 The Support Units

Conducted Emission Test

No.	Unit	Model No.	FCC ID	Trade Name	Power Cord	Supported by lab.
1	PC	Elite 8200 MT	DoC	HP	1.8m	✓
2	PS/2 Mouse	MO71KC	DoC	DELL	N/A	✓
3	PS/2 Keyboard	SK-8110	DoC	DELL	N/A	√
4	Monitor	U2410	DoC	DELL	1.8m	✓
5	Modem	DM-1414	IFAXDM1414	ACEEX	1.8m	✓
6	Printer	LQ-300+II	N/A	EPSON	1.8m	✓
7	USB 3.0 HDD	HD-PCTU3	DoC	BUFFALO	N/A	✓

Radiated Emission Test

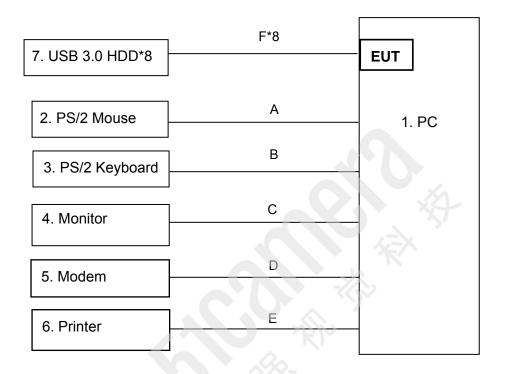
No.	Unit	Model No.	FCC ID	Trade Name	Power Cord	Supported by lab.
1	PC	Elite 8200 MT	DoC	HP	1.8m	✓
2	PS/2 Mouse	MO71KC	DoC	DELL	N/A	✓
3	PS/2 Keyboard	SK-8110	DoC	DELL	N/A	√
4	Monitor	U2410	DoC	DELL	1.8m	✓
5	Modem	DM-1414	IFAXDM1414	ACEEX	1.8m	✓
6	Printer	LQ-300+II	N/A	EPSON	1.8m	✓
		My Passport Essential	DoC	WD	N/A	✓
7	USB 3.0 HDD	HD-PCTU3	DoC	BUFFALO	N/A	✓
		My Passport	DoC	WD	N/A	✓

Other Tests

No.	Unit	Model No.	FCC ID	Trade Name	Power Cord	Supported by lab.
1	PC	Elite 8200 MT	DoC	HP	1.8m	✓
2	PS/2 Mouse	MO71KC	DoC	DELL	N/A	✓
3	PS/2 Keyboard	SK-8110	DoC	DELL	N/A	√
4	Monitor	2408WFP	DoC	DELL	1.8m	✓
5	Modem	DM-1414	IFAXDM1414	ACEEX	1.8m	✓
6	Printer	LQ-300+II	N/A	EPSON	1.8m	✓
		My Passport Essential	DoC	WD	N/A	✓
7	USB 3.0 HDD	HD-PCTU3	DoC	BUFFALO	N/A	√
'	030 3.0 NUD	HD-LX2.0TU3-AP	DoC	BUFFALO	1.5m	✓
		HD-LB2.0TU3-A2	DoC	BUFFALO	1.2m	✓

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TEL.: 886-2-25984542
FAX.: 886-2-25984546

1.6 Layout of the Setup



Connecting Cables:

No.	Cable	Length	Shielded	Core	Shielded Backshell	Supported by lab.	Note
Α	PS/2 Mouse Cable	1.8m	✓			✓	
IВ	PS/2 Keyboard Cable	2.0m	✓			✓	
С	VGA Cable	1.7m	✓	✓		✓	2 Cores
D	Modem Cable	1.8m	✓	✓		✓	2 Cores
Е	USB Cable	1.8m	✓	✓		✓	2 Cores
F	USB 3.0 Cable	1.0m	✓			✓	

1.7 Test Capability

Test Facility

The test facility used for evaluating the conformance of the EUT with each standard in the present report meets what required in CISPR16-1-4, CISPR16-2-3.

Test Room	Type of Test Room	Descriptions	
TR1	10m semi-anechoic chamber (23m×14m×9m)	requirements in documents CISPR 22 and	
TR1	3m fullly-anechoic chamber (23m×14m×9m)	CISPR 16-1-4 for the radiated emission measurement.	
TR11	3m semi-anechoic chamber (9m×6m×6m)	Complying with the NSA requirements set in documents CISPR 22/ EN 55022 for the radiated emission measurement.	
TR5	Shielding Room (8m×5m×4m)	For the conducted emission measurement.	
TR4	Shielding Room (5m×3m×3m)	To the conducted emission measurement.	
TR2	3m fully-anechoic chamber (7m×3m×3m)	Complying with the field uniformity requirements in standard IEC/ EN 61000-4-3 for the radiated immunity test.	
TR7	Shielding Room (5m×3m×3m)		
TR8	Shielding Room (5m×3m×3m)	For the Current Harmonic / Voltage Flicker	
AR	Shielding Room (3m×3m×3m)	and other immunity tests.	
TR12	Plane Grounding Site (2.4m×3m)		
TR300	3m fully-anechoic chamber (8m×5m×5m)	Complying with the site VSWR requirements set in documents CISPR 16-1-4 for the radiated emission measurement.	

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Test Laboratory Competence Information

Central Research Technology Co. has been accredited / filed / authorized by the agencies listed in the following table.

Certificate	Nation	Agency	Code	Mark
	USA	NVLAP	200575-0	ISO/IEC 17025
	R.O.C.	TAF	0905	ISO/IEC 17025
	(Taiwan)	IAI	0903	130/1LC 17023
Accreditation			SL2-IN-E-0033,	
Certificate	R.O.C.		SL2-IS-E-0033,	
		BSMI	SL2-R1/R2-E-0033,	ISO/IEC 17025
	(Taiwan)		SL2-A1-E-0033,	7
			SL2-L1-E-0033	>
	USA	FCC	474046,TW1053	Test facility list
	034	100	474040,1001000	& NSA Data
Site Filing	Canada	IC	4699A-1,-3	Test facility list
Document	Cariaua	iC	4099A-1,-3	& NSA Data
	Japan	VCCI	R-1527,C-1609, C-4400,	Test facility list
	Japan	VCCI	T-1441, T-1334, G-10, G-614	& NSA Data
Authorization	Germany	TUV	10021687	ISO/IEC 17025
Certificate	Norway	Nemko	ELA 212	ISO/IEC 17025

The copy of each certificate can be downloaded from our web site: www.crc-lab.com

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2. Conducted Emission Measurement

Test Result : PASS

2.1 Limits for Emission Measurement

☑ Limits for conducted disturbances at the power mains

Frequency (MHz)	Class A E	quipment	Class B Equipment		
	Quasi-peak	Average	Quasi-peak	Average	
	(dBµV)	(dBµV)	(dBµV)	(dBµV)	
0.15 to 0.5	79	66	66 - 56	56 – 46	
0.5 to 5	73	60	56	46	
5 to 30	73	60	60	50	

Note 1- The lower limit shall apply at the transition frequency.

Note 2- The limit decreases linearly with the logarithm of the frequency in the range 0.15 MHz to 0.5MHz for Class B equipment.

☐ Limits for conducted common mode disturbances at telecommunication ports

	Class A Equipment				Class B Equipment			
Frequency	Voltage	e Limits	Curren	t Limits	Voltage	e Limits	Curren	t Limits
(MHz)	Q.P.	Average	Q.P.	Average	Q.P.	Average	Q.P.	Average
	(dBµV)	(dBµV)	(dBµA)	(dBµA)	(dBµV)	(dBµV)	(dBµA)	(dBµA)
0.15 to 0.5	97 - 87	84 – 74	53 – 43	40 – 30	84 – 74	74 - 64	40 – 30	30 - 20
0.5 to 30	87	74	43	30	74	64	30	20

Note 1- The limit decreases linearly with the logarithm of the frequency in the range 0.15 MHz to 0.5MHz.

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Note 2- The current and voltage disturbance limits are derived for use with an impedance stabilization network (ISN) which presents a common mode (asymmetric mode) impedance of 150Ω to the telecommunication port under test.

2.2 Test Instruments

Test Site and	Manufacturer	Model No./	Last	Calibration	
Equipment	Mariuracturer	Serial No.	Calibration Date	Due Date	
Test Receiver	R&S	ESCS 30/	Jan. 14, 2013	Jan. 14, 2014	
163t Neceivei	Nao	836858/021	Jan. 14, 2013	Jan. 14, 2014	
LISN	R&S	ESH2-Z5/	March 15, 2013	March 15, 2014	
LIOIT	1100	880669/039	Waron 10, 2010	Widion 10, 2014	
2 nd LISN	R&S	ENV4200/	March 29, 2013	March 29, 2014	
Z LIOIV	1100	833209/010	Wardin 25, 2015	Water 25, 2014	
		☐ FCC-TLISN-T2-02/	August 13, 2013	August 13, 2014	
	FCC	20269	/tagast 10, 2010	7 tagaot 10, 2014	
Balanced		☐ FCC-TLISN-T4-02/	April 1, 2013	April 1, 2014	
TELE. ISN		20270	7,0111 1, 2010	7.5, 20	
		☐ FCC-TLISN-T8-02/	Dec. 28, 2012	Dec. 28, 2013	
		20318	500. 20, 2012	200. 20, 2010	
50Ω terminator	N/A	N/A/	Aug. 19, 2013	Aug. 19, 2014	
		001	,g. 10, _010	7tug. 13, 2014	
RF Switch	R&S	RSU28/	Aug. 19, 2013	Feb. 19, 2014	
		338965/002	7 ta.g. 10, 2010		
RF Cable	N/A	N/A/	Aug. 19, 2013	Feb. 19, 2014	
111 04510	147	C0052 ~ 56	7 tag. 10, 2010	1 60. 19, 2014	
Test Software	Audix	e3/	NCR	NCR	
		Ver. 5.2004-2-19k	11011		
TR5	ETS	TR5/	NCR	NCR	
shielded room	LINDGREN	15353-F	11011	INCIX	

Note:

1. The calibrations are traceable to NML/ROC.

2. NCR: No Calibration Required.

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Measurement Uncertainty

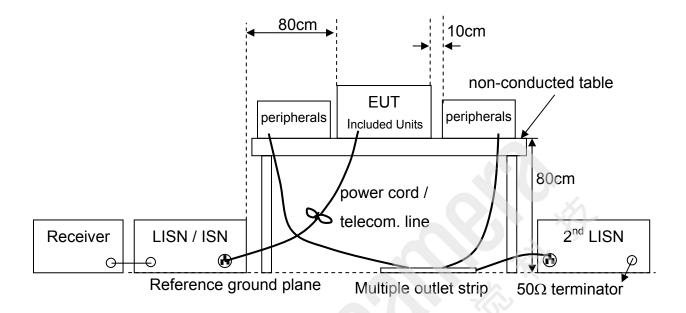
The assessed measurement uncertainty with a suitable coverage factor K to ensure 95% confidence level for the normal distribution are shown as below, the values are less than U_{cispr} in table 1 of CISPR 16-4-2.

Equipment	Model Number	Uncertainty Value
LISN	ESH2-Z5	3.0dB
LION	ENV 4200	3.0dB
	FCC-TLISN-T2-02	3.2dB
ISN	FCC-TLISN-T4-02	3.2dB
	FCC-TLISN-T8-02	3.2dB

2.3 Test Procedures

- a. The EUT was set up per the test configuration figured in the next section of this chapter to simulate the typical usage per the user's manual.
- b. If the EUT is tabletop equipment, it was placed on a wooden table with a height of 0.8 meters above the reference ground plane and 0.4 meters from the conducting wall of the shielded room. Also if the EUT is floor-standing equipment, it was placed on a non-conducted support with a height up to 0.15 meters above the reference ground plane.
- c. Connect the EUT's power source / telecommunication lines to the appropriate power mains / peripherals through the LISN / ISN.
- d. All the other peripherals are connected to the 2nd LISN, if any.
- e. The LISN / ISN was placed 0.8 meters from the EUT and at least 0.8 meters from other units and other metal planes.
- f. Measure the conducted emissions on each power line (Neutral Line and Line 1 Hot side) of the EUT's power source by using the test receiver connected to the coupling RF output port of LISN.
- g. Rapidly scan the signal from 150kHz to 30MHz by using the receiver through the Maximum-Peak detector to determine those frequencies associated with higher emission levels for each measured line.
- h. Then measure the maximum level of conducted disturbance for each frequency found from step g. by using the receiver through the Quasi-Peak and Average detectors per CISPR 16-1.
- i. Record the level for each frequency and compare with the required limit.
- j. If required, measure the conducted emissions on telecommunication lines of EUT by using the test receiver connected to the coupling RF output port of ISN and repeat step g. to i.
- k. If the peak emission level is lower than the specified Average limit, then the emission values presented will be the peak value only. Otherwise, accurate Q.P. or Average values will be measured and presented.

2.4 Test Configurations



2.5 Photographs of the Test Configurations

Please refer to the Attachment 1 of the present report.

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2.6 Test Results

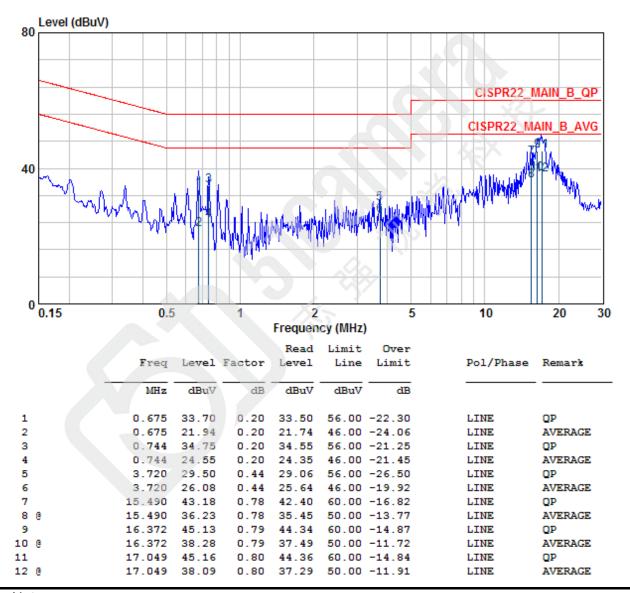
Test Mode : Normal

Test Voltage: 230V/50Hz to the connected PC

Tester: Kent **Temperature**: 27°C

Humidity: 50%RH Frequency Range: 150kHz~30MHz

IF Bandwidth: 9kHz Phase : Line



Note:

- 1. Emission Level = reading value + correction factor.
- 2. Correction factor = cable loss + insertion loss of LISN.
- Q.P. is abbreviation of quasi-peak.
- 4. If the limit for the measurement with the average detector is met when using a receiver with a quasi-peak detector, the EUT shall be deemed to meet both limits.

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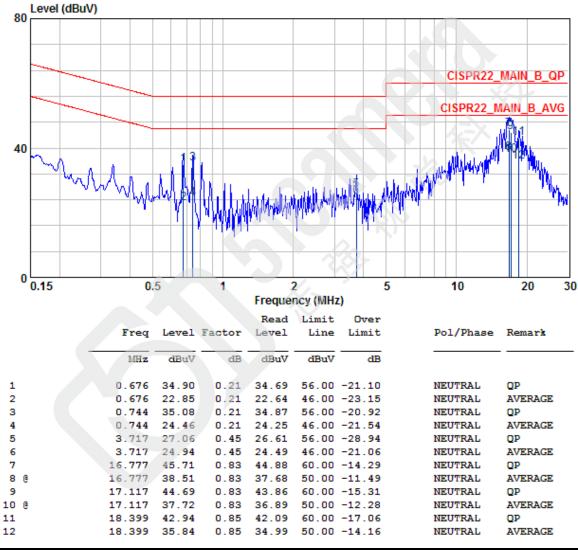
Test Mode : Normal

Test Voltage: 230V/50Hz to the connected PC

Tester: Kent **Temperature**: 27°C

Humidity: 50%RH Frequency Range: 150kHz~30MHz

IF Bandwidth: 9kHz Phase : Neutral



Note:

- 1. Emission Level = reading value + correction factor.
- Correction factor = cable loss + insertion loss of LISN.
- Q.P. is abbreviation of quasi-peak.
- 4. If the limit for the measurement with the average detector is met when using a receiver with a quasi-peak detector, the EUT shall be deemed to meet both limits.

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Radiated Emission Measurement 3.

Test Result : PASS

Limits for Emission Measurement 3.1

Type of EUT	Highest frequency generated or used in the device or on which the device operates or tunes (MHz)	Upper frequency of measurement range (MHz)
	Below 108	1000
	108 - 500	2000
	500 - 1000	5000
V	Above 1000	5 th harmonic of the highest frequency or 6GHz, whichever is lower

☑ Limits for radiated disturbances at a measuring distance of 10m

Frequency	Class A Equipment	Class B Equipment
(MHz)	Quasi-peak (dBµV/m)	Quasi-peak (dBµV/m)
30 to 230	40	30
230 to 1000	47	37
Note 1- The lower lim	it shall apply at the transition frequency.	

Note 2- Additional provisions may be required for cases where interference occurs.

☑ Limits for radiated disturbances at a measuring distance of 3m

Frequency	Class A E	quipment	Class B Equipment		
(GHz)	Peak (dBµV/m)	Average (dBµV/m)	Peak (dBµV/m)	Average (dBµV/m)	
1 to 3	76	56	70	50	
3 to 6	80	60	74	54	
Note 1- The lower limit shall apply at the transition frequency.					

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3.2 Test Instruments

☑ Below 1GHz measurement

Test Site and	Manufacturer	Model No./	Last	Calibration
Equipment	Manaraotarer	Serial No.	Calibration Date	Due Date
EMI Test Receiver	R&S	ESCS 30/ 836858/020	Sept. 9, 2013	Sept. 9, 2014
Broadband Antenna	R&S	HL-562/ 360543/007	March 27, 2013	March 27, 2014
Broadband Antenna	R&S	HL-562/ 830547/010	April 30, 2013	April 30, 2014
Pre-Amplifier	Mini Circuit	ZKL-2/ 001	July 15, 2013	Jan. 15, 2014
Pre-Amplifier	Mini Circuit	ZKL-2/ 002	July 15, 2013	Jan. 15, 2014
Spectrum Analyzer	R&S	FSP7/ 100108	August 19, 2013	August 19, 2014
Spectrum Analyzer	R&S	FSP7/ 100384	Jan. 10, 2013	Jan. 10, 2014
RF Cable	JYEBAO	0214/ C0049	July 15, 2013	Jan. 15, 2014
RF Cable	JYEBAO	0214/ C0050	July 15, 2013	Jan. 15, 2014
Test Software	Audix	e3/ Ver. 4.3.714.e	NCR	NCR
TR1 Semi - anechoic Chamber	ETS. LINDGREN	TR1/ 17627-B	May 4, 2013	May 4, 2014

Note:

- 1. The calibrations are traceable to NML/ROC.
- 2. NCR: No Calibration Required.
- 3. The calibration date of the chamber TR1 listed above is the date of NSA measurement.

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☑ Above 1GHz measurement (TR1)

Test Site and Equipment	Manufacturer		Model No./ Serial No.	Last Calibration Date	Calibration Due Date
Horn Antenna	EMCO	3117/ 00082847		March 5, 2013	March 5, 2014
Bore-sight Antenna Mast	Sunol	TLT2/ 051110-5		NCR	NCR
	KMIC		KMA010180A01/ 99056	Oct. 17, 2013	Oct. 17, 2014
Pre-Amplifier	MITEQ	V	JS4-00101800- 28-10P/1498979	Dec. 21, 2012	Dec. 21, 2013
			JS4-00101800- 28-5A/742309	Dec. 19, 2012	Dec. 19, 2013
Spectrum Analyzer	R&S		FSP40/ 100031	July 15, 2013	July 15, 2014
RF Cable	Suhner	Sucoflex 106P / C0091 + C0092		Oct. 14, 2013	April 14, 2014
Test Software	Audix	e3/ Ver. 4.3.714.e		NCR	NCR
TR1 Fully - anechoic Chamber	ETS. LINDGREN		TR1/ 17627-B	Feb. 23, 2013	Feb. 23, 2014

Note:

- 1. The calibrations are traceable to NML/ROC.
- 2. NCR: No Calibration Required.
- The calibration date of the chamber TR1 listed above is the date of site VSWR measurement.

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Measurement Uncertainty

The assessed measurement uncertainty with a suitable coverage factor K to ensure 95% confidence level for the normal distribution are shown as below, the values are less than U_{cispr} in table 1 of CISPR 16-4-2.

Test Site	Polarization	Frequenc	cy Range
(Measuring distance)	1 Glarization	30MHz ~200MHz	200MHz ~1000MHz
TR1(10m)	Horizontal	3.7dB	3.7dB
	Vertical	3.5dB	3.9dB

Test Site (Measuring distance)	Polarization	Frequency Range 1GHz ~6GHz
TD4/2m)	Horizontal	4.8dB
TR1(3m)	Vertical	4.8dB
TD200(2m)	Horizontal	4.8dB
TR300(3m)	Vertical	4.8dB

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3.3 Test Procedures

Below 1GHz measurement

- a. The EUT was set up per the test configuration figured in the next section of this chapter to simulate the typical usage per the user's manual.
- b. If the EUT is tabletop equipment, it was placed on a wooden table with a height of 0.8 meters above the reference ground plane and 10 meters away from the interference receiving antenna in the semi-anechoic chamber.
- c. If the EUT is floor-standing equipment, it was placed on a non-conducted support with a height up to 0.15 meters above the reference ground plane and 10 meters away from the interference-receiving antenna in the semi-anechoic chamber.
- d. Rapidly sweep the signal from 30MHz to 1GHz by using the spectrum through the Maximum-peak detector.
- e. Rotate the EUT from 0° to 360° and position the receiving antenna at heights from 1 to 4 meters above the reference ground plane continuously to determine at least six frequencies associated with higher emission levels and record them.
- f. Then measure each frequency found from step e. by using the spectrum with rotating the EUT and positioning the receiving antenna height to determine the maximum level.
- g. Finely tune the antenna and turntable around the recorded position of each frequency found from step f. by using the receiver through the Quasi-Peak detector per CISPR 16-1 to find out where the maximum level occurred.
- h. Record frequency, azimuth angle of the turntable, height, and polarization of the receiving antenna and compare the maximum level with the required limit.
- i. Change the receiving antenna to another polarization to measure radiated emission by following step d. to h. again.
- j. If the peak emission level measured from step e. is 4dB lower than the limit specified, then the emission values presented will be the peak value only. Otherwise, accurate Q.P. value will be measured and presented.

Above 1GHz measurement

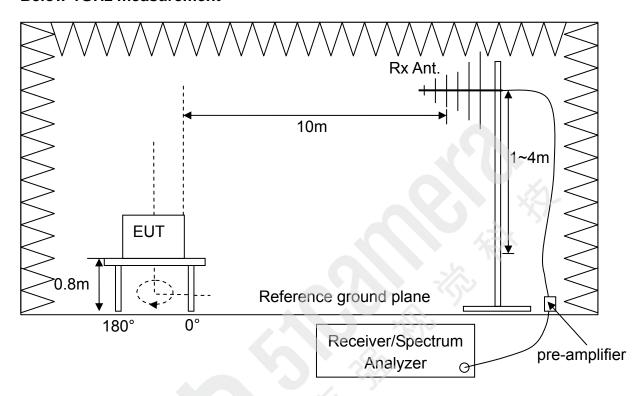
- a. The EUT was set up per the test configuration figured in the next section of this chapter to simulate the typical usage per the user's manual.
- b. If the EUT is tabletop equipment, it should be placed on a non-conducted table with a height of 0.8 meters above the reference ground plane and 3 meters away from the interference receiving antenna in the fully-anechoic chamber.
- c. If the EUT is floor-standing equipment, it should be placed on a non-conducted support with a height up to 0.15 meters above the reference ground plane and 3 meters away from the interference-receiving antenna in the fully-anechoic chamber.
- d. Rapidly sweep the signal from 1GHz to the upper frequency of measurement range by using the spectrum through the Maximum-peak detector.
- e. Rotate the EUT from 0° to 360° continuously and position the receiving antenna at specified height above the reference ground plane to determine the frequencies associated with higher emission levels and record them.
- f. Then measure each frequency found from step e. by using the spectrum with rotating the EUT to determine the maximum peak and average level.
- g. Record frequency, azimuth angle of the turntable and compare the maximum level with the required limit.
- h. Change the receiving antenna to another polarization to measure radiated emission by following step d. to g. again.

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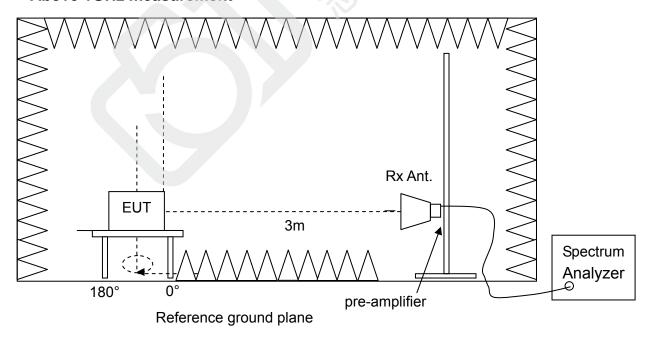
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3.4 Test Configurations

Below 1GHz measurement



Above 1GHz measurement



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3.5 Photographs of the Test Configurations

Please refer to the Attachment 1 of the present report.



3.6 **Test Results**

Radiated Emission Measurement below 1000MHz

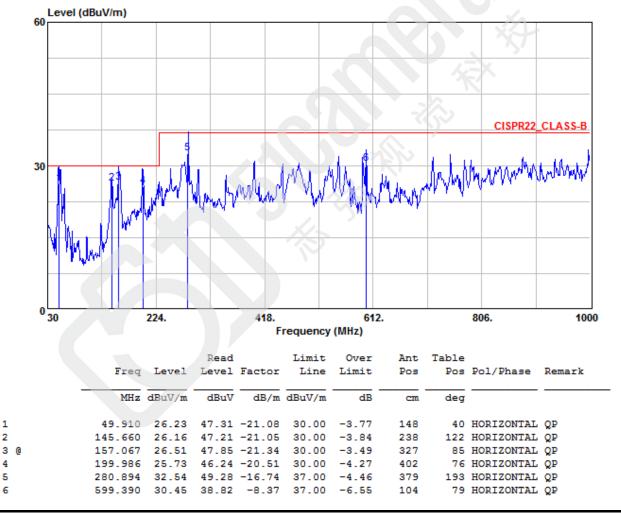
Test Mode Normal

Test Voltage 230V/50Hz to the connected PC

Tester Carl **Temperature** 23°C

Humidity 69%RH **Frequency Range** 30MHz~1GHz

IF Bandwidth: 120kHz **Polarization** Horizontal



Note:

5

- Emission Level = reading value + correction factor. 1.
- Correction factor = cable loss + antenna factor gain of pre-amplifier. 2.
- Q.P is abbreviation of quasi-peak.

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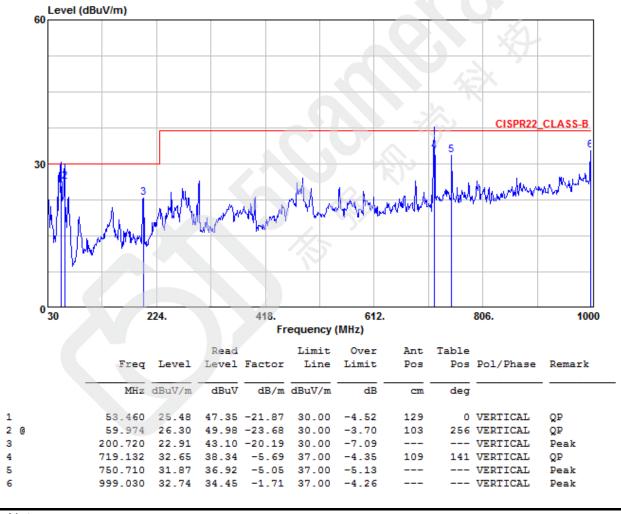
Test Mode : Normal

Test Voltage: 230V/50Hz to the connected PC

Tester : Carl Temperature : 23°C

Humidity: 69%RH Frequency Range: 30MHz~1GHz

IF Bandwidth: 120kHz Polarization: Vertical



Note:

- 1. Emission Level = reading value + correction factor.
- 2. Correction factor = cable loss + antenna factor gain of pre-amplifier.
- Q.P is abbreviation of quasi-peak.

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Radiated Emission Measurement above 1000MHz

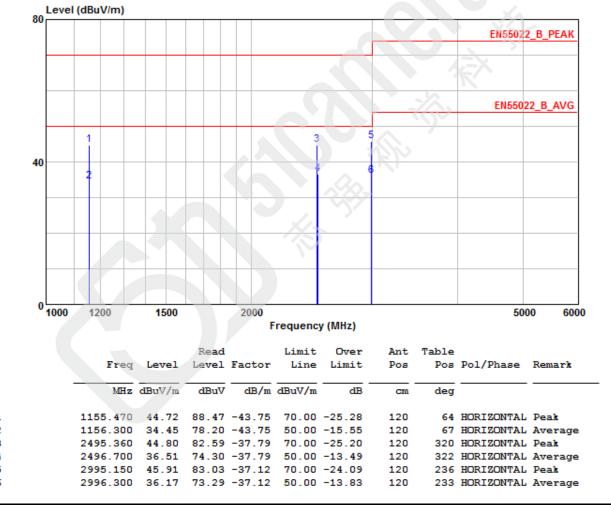
Test Mode : Normal

Test Voltage: 230V/50Hz to the connected PC

Tester: Carl **Temperature**: 26°C

Humidity: 69%RH Frequency Range: 1GHz~6GHz

IF Bandwidth: 1MHz Polarization: Horizontal



Note:

- 1. Emission Level = reading value + correction factor.
- 2. Correction factor = cable loss + antenna factor gain of pre-amplifier.

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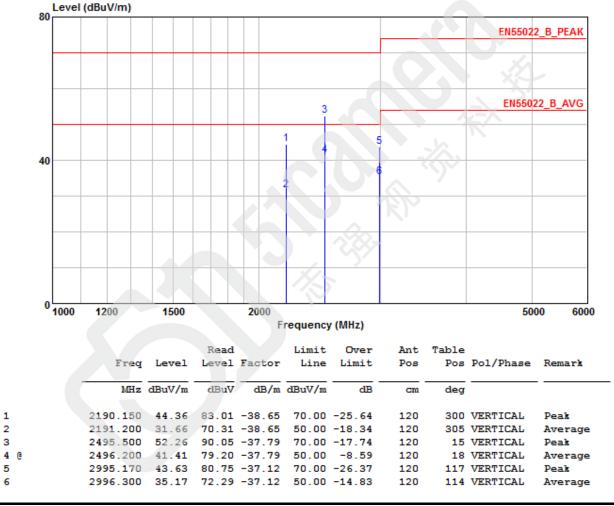
Test Mode : Normal

Test Voltage: 230V/50Hz to the connected PC

Tester: Carl **Temperature**: 26°C

Humidity: 69%RH Frequency Range: 1GHz~6GHz

IF Bandwidth: 1MHz Polarization: Vertical



Note:

- Emission Level = reading value + correction factor.
- 2. Correction factor = cable loss + antenna factor gain of pre-amplifier.

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4. Harmonic Current Emission Measurement

Test Result : PASS

4.1 Limits for Emission Measurement

☐ Limits for Class A equipment

Harmonic order (n) Maximum permissible		Harmonic order (n)	Maximum permissible
Odd harmonics	harmonic current (A)	Even Harmonics	harmonic current (A)
3	2.30	2	1.08
5	1.14	4	0.43
7	0.77	6	0.3
9	0.40	8 n 40	0.23 8/n
11	0.33		=\
13	0.21		
15 n 39	0.15 15/n		

☐ Limits for Class B equipment

It shall not exceed the vales give in calss A multiplied by a factor of 1.5.

☐ Limits for Class C equipment

Harmonic order (n)	Maximum permissible harmonic current expressed as a percentage of the input current at the fundamental frequency %	
2	2	
3	30·λ (λ is the circuit power factor)	
5	10	
7	7	
9	5	
11 ≤ n ≤ 39	3	
(odd harmonics only)		

☑ Limits for Class D equipment

Harmonic order (n)	Maximum permissible harmonic	Maximum permissible harmonic
	current per watt (mA/W)	current (A)
3	3.4	2.30
5	1.9	1.14
7	1.0	0.77
9	0.5	0.40
11	0.35	0.33
13 ≤ n ≤ 39	3.85/n	See class A
(odd harmonics only)		

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Test Instruments 4.2

Test Site and	Manufacturer	Model No./	Last	Calibration	
Equipment	Wandacture	Serial No.	Calibration Date	Due Date	
Power Source		5001ix-208/	Oct. 17, 2013	Oct 17 2014	
Power Source	California	56619	Oct. 17, 2013	Oct. 17, 2014	
Dower Apolyzor	Instrument	PACS-1/	Oct. 17, 2013	Oct. 17, 2014	
Power Analyzer		72398	Oct. 17, 2013		
Test Software	C.I.	CTS 3.0/	NCR	NCD	
Test Software	C.I.	Ver. 3.2.0.35	NCK	NCR	
TR7	ETS.	TR7/	NCR	NCD.	
shielded room	LINDGREN	15353-D	NCK	NCR	

Note:

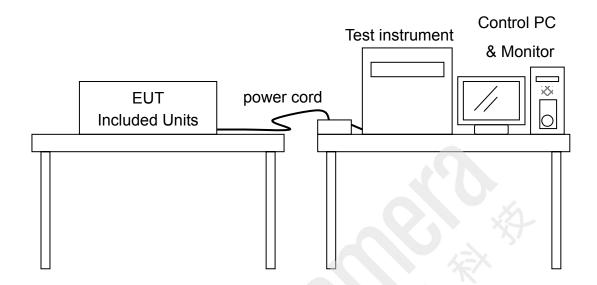
- The calibrations are traceable to NML/ROC.
- NCR: No Calibration Required. 2.

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Test Procedures 4.3

- a. The EUT was set up per the test configuration figured in the next section of this chapter to simulate the typical usage per the user's manual.
- b. If the EUT is tabletop equipment, it was placed on a wooden table with a height of 0.8 meters in the shielded room.
- c. If the EUT is floor-standing equipment, it was placed on a non-conducted support with a height of 0.1 meters in the shielded room.
- d. Decide the classification of the EUT as following:
 - Class A: balanced three-phase equipment
 - household appliances, excluding equipment identified as class D
 - tools, excluding portable tools
 - dimmers for incandescent lamps
 - audio equipment
 - equipments not specified in one of the three other classes
 - Class B: portable tools
 - arc welding equipment which is not professional equipment.
 - Class C: lighting equipment
 - Class D: Equipment specified power less than or equal to 600W of the following types
 - personal computers and personal computer monitors
 - television receivers
- e. Connects the EUT's power source to the mains power supplied by the test instrument. Turn on the EUT.
- f. Operating the EUT as required and measuring the harmonic current emissions on the current carrying lines of EUT's power source.

4.4 Test Configurations



4.5 Photographs of the Test Configurations

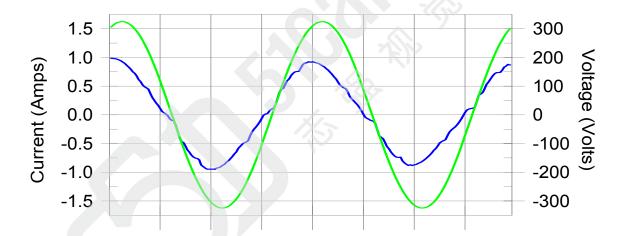
Please refer to the Attachment 1 of the present report.

4.6 Test Results

Test Mode : Normal
Tester : Eddie
Temperature : 24°C

Humidity: 32%RH

TEST FREQ	50 Hz
TEST VOLTS	230 Vac
TEST TIME	10 Minutes
MAX WATTS	134.8 W



Test	Raw	Data:
1001	11411	Data.

Harm#	Harms(avg)	100%l imit	%of Limit	Harms(max)	150%l imit	%of Limit	Status
2	0.000	100702111111	7001 Ellillit	riaimo(max)	100 /0 2 111111	7001 Ellillic	Otatuo
3	0.040	0.458	8.7	0.039	0.546	7.17	Pass
4	0.000	000		0.000	0.0.0		
5	0.007	0.256	2.7	0.010	0.305	3.26	Pass
6	0.000						
7	0.012	0.135	9.1	0.013	0.161	7.97	Pass
8	0.000						
9	0.007	0.067	11.1	0.011	0.101	11.02	Pass
10	0.000						
11	0.003	0.047	5.4	0.000	0.000	0.00	Pass
12	0.000						
13	0.008	0.040	19.8	0.010	0.055	17.43	Pass
14	0.000						
15	0.009	0.035	24.3	0.012	0.051	24.52	Pass
16	0.000						
17	0.003	0.031	9.2	0.000	0.000	0.00	Pass
18	0.000						
19	0.004	0.027	16.4	0.009	0.033	27.69	Pass
20	0.000						
21	0.006	0.025	24.6	0.008	0.036	22.72	Pass
22	0.000						
23	0.003	0.023	13.7	0.000	0.000	0.00	Pass
24	0.000						
25	0.003	0.021	15.9	0.000	0.000	0.00	Pass
26	0.000						
27	0.004	0.019	18.2	0.000	0.000	0.00	Pass
28	0.000						
29	0.002	0.018	10.7	0.000	0.000	0.00	Pass
30	0.000						
31	0.002	0.017	11.5	0.000	0.000	0.00	Pass
32	0.000						
33	0.002	0.016	13.6	0.000	0.000	0.00	Pass
34	0.000						_
35	0.002	0.015	11.1	0.000	0.000	0.00	Pass
36	0.000		4.				_
37	0.001	0.014	10.6	0.000	0.000	0.00	Pass
38	0.000	0.040	0.0	0.000	0.000	0.00	D
39	0.001	0.013	8.6	0.000	0.000	0.00	Pass
40	0.000						

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FAX.: 886-2-25984546

5. **Voltage Fluctuations and Flickers Emission Measurement**

Test Result : PASS

Limits for Emission Measurement 5.1

- the short-term flicker indicator, P_{st}, shall not be greater than 1.0;
- the long-term flicker indicator, P_{lt}, shall not be greater than 0.65;
- the relative steady-state voltage change, dc, shall not exceed 3.3%;
- the voltage change with time, d(t), during a voltage change shall not exceed 3.3% for more than 500ms.
- the maximum relative voltage change, d_{max}, shall not exceed
 - ☑ a) 4% without additional conditions;
 - □ b) 6% for equipment which is switched manually
 - ☐ c) 7% for equipment which is attended whilst in use

5.2 **Test Instruments**

Test Site and	Manufacturer	Model No./	Last	Calibration	
Equipment	Wandacture	Serial No.	Calibration Date	Due Date	
Power Source		5001ix-208/	Oct. 17, 2013	Oct 17 2014	
Power Source	California	56619	OCI. 17, 2013	Oct. 17, 2014	
Power Analyzer	Instrument	PACS-1/	Oct. 17, 2013	Oct. 17, 2014	
Fower Analyzer		72398	OCI. 17, 2013		
Test Software	C.I.	CTS 3.0/	NCR	NCR	
Test Software	C.I.	Ver. 3.2.0.35	NCR	NCR	
TR7	ETS.	TR7/	NCR	NCR	
shielded room	LINDGREN	15353-D	NOR	NOR	

Note:

The calibrations are traceable to NML/ROC. 1.

2. NCR : No Calibration Required.

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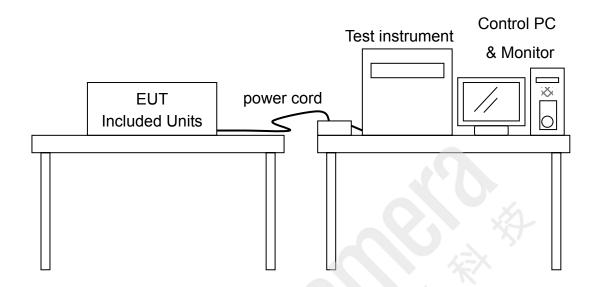
5.3 Test Procedures

- a. The EUT was set up per the test configuration figured in the next section of this chapter to simulate the typical usage per the user's manual.
- b. If the EUT is tabletop equipment, it was placed on a wooden table with a height of 0.8 meters in the shielded room.
- c. If the EUT is floor-standing equipment, it was placed on a non-conducted support with a height of 0.1 meters in the shielded room.
- d. Decide the type of EUT to define the d_{max} limit and its corresponding test methods described in the relative standard.
- e. Maintain the supply voltage to be $\pm 2\%$ of the EUT's rated voltage and also the frequency to be 50Hz $\pm 0.5\%$.
- f. Connects the EUT's power source to the mains power supplied by the test instrument.
- g. Operating the EUT as required and measuring the voltage fluctuation and flickers of EUT's power source.
- h. Verify the fluctuations of the test supply voltage to be less than 0.4 before and after the test.

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5.4 Test Configurations



5.5 Photographs of the Test Configurations

Please refer to the Attachment 1 of the present report.

5.6 Test Results

Test Mode Normal Eddie **Tester Temperature** 24°C **Humidity**

32%RH

TEST FREQ	50 Hz	
TEST VOLTS	230 Vac	
TEST TIME	10 Minutes	1/0
	EUT Data	Limit
d(t)>3.3% (ms)	0	500
d _c (%)	0	3.3
d _{max} (%)	0	4
P _{st} max	0.064	1
P _{lt} max	0.028	0.65



6. Electrostatic Discharge (ESD) Immunity Test

Test Result : PASS

6.1 Specifications of Immunity Test Requirement

Product (Generic) Standard : EN 55024:2010

Basic Standard : EN 61000-4-2:2009

Required Performance : B

Test Level : 2 (Contact discharge)

3 (Air discharge)

Discharge Voltage : Contact →±4kV (Direct / Indirect discharge)

Air $\rightarrow \pm 2kV$, $\pm 4kV$, $\pm 8kV$ (Direct discharge)

Time Interval : 1 sec. minimum

Number of discharges : Minimum 20 times at each test point

Test Voltage : 230V/50Hz to the connected PC

Tester : Eddie

Ambient Temperature : 24°C

Relative Humidity : 38%

Atmospheric Pressure : 1025mbar

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6.2 Description of Performance Criteria

Criteria A: normal performance within levels specified by the manufacturer,

requestor or purchaser;

Criteria B: temporary loss of function or degradation of performance which ceases

after the disturbance ceases, and from which the EUT recovers its

normal performance, without operator intervention;

Criteria C: temporary loss of function or degradation of performance, the correction

of which requires operator intervention;

Criteria D: loss of function or degradation of performance which is not recoverable,

owing to damage to hardware or software, or loss of data.

6.3 Test Instruments

Test Site and Equipment	Manufacturer	Model No./ Serial No.	Last Calibration Date	Calibration Due Date
Electrostatic Generator	EM TEST	DITO/ V1138110834	July 15, 2013	July 15, 2014
TR8 shielded room	ETS. LINDGREN	TR8/ 15353-C	NCR	NCR

Note:

1. The calibrations are traceable to NML/ROC.

2. NCR: No Calibration Required.

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6.4 Test Procedures

- a. The EUT was set up per the test configuration figured in the next section of this chapter to simulate the typical usage per the user's manual.
- b. If the EUT is tabletop equipment, it was placed on a wooden table with a height of 0.8 meters above the ground reference plane in the shielded room. Also a HCP (Horizontal Coupling Plane) which was connected to the ground reference plane via a cable with a $470 \mathrm{k}\Omega$ resister located at each end was placed on the wooden table and isolated with the EUT by an insulating support 0.5mm thick. The ground reference plane shall project beyond the EUT or HCP by at least 0.5m on all sides.
- c. If the EUT is floor-standing equipment, it was placed on a non-conducted support with a height of 0.1 meters above the ground reference plane in the shielded room. The ground reference plane shall project beyond the EUT by at least 0.5m on all sides.
- d. Keep the EUT 1m away from all other metallic walls in the shielded room as the minimum distance.
- e. The static electricity discharges shall be applied only to those points and surfaces of the EUT which are accessible to persons during normal use. Contact discharge is the preferred test method and it is applied to the conductive surfaces of EUT and coupling planes. Air discharge shall be used where contact discharge cannot be performed and it is applied to the insulating surfaces of EUT.
- f. The discharge return cable of the generator shall be kept at a distance of at least 0.2m from the EUT whilst the discharge is being applied.
- g. The time interval between successive single discharges was at least 1 second.
- h. Select appropriate points of the EUT for contact discharge and put marks on it to indicate the tested point(s). Then start the contact discharge with the tip of the discharge electrode to touch the EUT before the discharge switch is operated.
- i. Use the round discharge tip of the discharge electrode to scan the EUT to select the points for air discharge. Then start the air discharge by approaching the discharge electrode as fast as possible to touch the EUT. After each discharge, the ESD generator shall be removed from the EUT.
- j. The indirect HCP discharge test is applied at the front edge of each HCP opposite the center point of each unit of the EUT and 0.1m from the front of the EUT. The long axis of the discharge electrode shall be in the plane of the HCP and perpendicular to its front edge during the discharge.

k. The indirect VCP (Vertical Coupling Plane) discharge test is applied to the center of one vertical edge of the coupling plane. The VCP, of dimensions 0.5m×0.5m, is placed parallel to, and positioned at a distance of 0.1m from the EUT. It shall be applied with sufficient different positions such that the four faces of the EUT are completely illuminated.

Special Test Requirements for Information Technology Equipment (ITE)

The discharges shall be applied in two ways as below:

a. Contact discharges to the conductive surfaces and coupling planes:

The EUT shall be exposed to at least 200 discharges, 100 each at negative and positive polarity, at a minimum of four test points. One of the test points shall be subjected to at least 50 indirect discharges to the center of the front edge of the horizontal coupling plane. The remaining three test points shall each receive at least 50 direct contact discharges. If no direct contact test points are available, at least 200 indirect discharges shall be applied in the indirect mode (for use of the VCP).

b. Air discharges at slots and apertures and insulating surfaces:

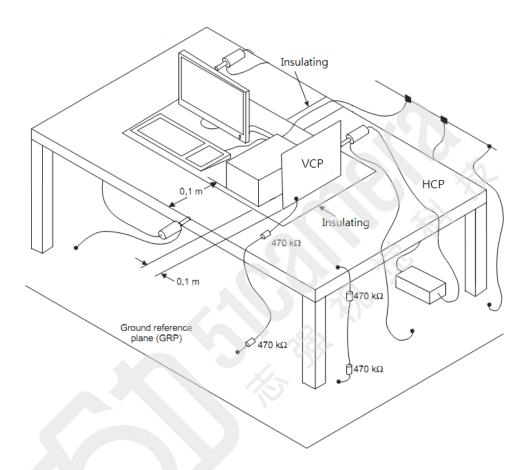
A minimum of 10 single air discharges shall be applied to the each selected test point.

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6.5 Test Configurations



6.6 Photographs of the Test Configurations

Please refer to the Attachment 1 of the present report.

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6.7 Test Results

Test Mode : Normal

Discharge	Type of	Label for	Perfo	rmance	Result
Voltage (kV)	discharge	Dischargeable Points	Required	Observation	
+4	Contact	1,2	В	A(1)	Pass
T-4	Contact	3	В	B(2)	Pass
-4	Contact	1,2,3	В	A(1)	Pass
±2	Air	No dischargeable point	В	A(1)	Pass
±4	Air	No dischargeable point	В	A(1)	Pass
±8	Air	No dischargeable point	В	A(1)	Pass
±4	HCP-Bottom	Edge of the HCP	В	A(1)	Pass
±4	VCP-Front	Center of the VCP	В	A(1)	Pass
±4	VCP-Left	Center of the VCP	В	A(1)	Pass
±4	VCP-Back	Center of the VCP	В	A(1)	Pass
±4	VCP-Right	Center of the VCP	В	A(1)	Pass

Observation of Performance during Test

- (1) Normal operation condition specified by manufacturer during the test.
- (2) The USB Device would function off while test is performing, it could self-recover after the test.

Photographs of the Dischargeable Points on the EUT for ESD Test



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7. Radiated Electromagnetic Field (RS) Immunity Test

Test Result : PASS

7.1 Specifications of Immunity Test Requirement

Product (Generic) Standard : EN 55024:2010

Basic Standard : EN 61000-4-3:2006+A1:2008+A2:2010

Required Performance : A

Test Level : 2

Field Strength : 3 V/m

Test Frequency Range : 80MHz ~ 1GHz

Frequency Step : 1% of the momentary frequency

Dwell Time : Minimum 3 sec. per frequency

Modulation : 1kHz Sine Wave with 80% Amplitude Modulation

Polarization of Antenna : Horizontal and Vertical

Test Voltage : 230V/50Hz to the connected PC

Tester : Eddie
Ambient Temperature : 23°C
Relative Humidity : 34%

Atmospheric Pressure : 1025mbar

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7.2 Description of Performance Criteria

Criteria A: normal performance within levels specified by the manufacturer,

requestor or purchaser;

Criteria B: temporary loss of function or degradation of performance which ceases

after the disturbance ceases, and from which the EUT recovers its

normal performance, without operator intervention;

Criteria C: temporary loss of function or degradation of performance, the correction

of which requires operator intervention;

Criteria D: loss of function or degradation of performance which is not recoverable,

owing to damage to hardware or software, or loss of data.

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7.3 Test Instruments

Test Site and Equipment	Manufacturer	Model No./ Serial No.	Last Calibration Date	Calibration Due Date
Signal Generator	R&S	SML03/ 101676	July 15, 2013	July 15, 2014
Switch Box	AR	SC1000M3/ 309064	NCR	NCR
Dual Directional	AR	DC6180/ 28730	Jan. 3, 2013	Jan. 3, 2014
Coupler	AR	DC 7144A/ 308731	May 7, 2013	May 7, 2014
Power	TESEQ	CBA 1G-275/ T44287	NCR	NCR
Amplifier	AR	30S1G3/ 308785	NCR	NCR
	EMCO	3142B/ 1716	NCR	NCR
Bi-Log Antenna	R&S	HL046/ 359132/004	NCR	NCR
	TRC	TRC Horn/ 001	NCR	NCR
Field Monitor	AR	FM7004/ 0336364	NCR	NCR
Electric Field Probe	AR	FL7006/ 0336500	April 16, 2013	April 16, 2014
Dual Channel Power Meter	R&S	NRVD/ 100499	Jan. 4, 2013	Jan. 4, 2014
Power Sensor	R&S	URV5-Z2/ 835640/013	Jan. 4, 2013	Jan. 4, 2014
1 OWEI OCIISOI	R&S	URV5-Z2/ 100731	Jan. 4, 2013	Jan. 4, 2014
Test Software	Audix	i2/ V5.10.5	NCR	NCR
TR2 fully- anechoic chamber	ETS. LINDGREN	TR2/ 15353-R	Sept. 16, 2013	Sept. 16, 2014

Note:

- 1. The calibrations are traceable to NML/ROC.
- 2. NCR: No Calibration Required.
- 3. The calibration date of the fully-anechoic chamber listed above is the date of Field Uniformity Calibration measurement.

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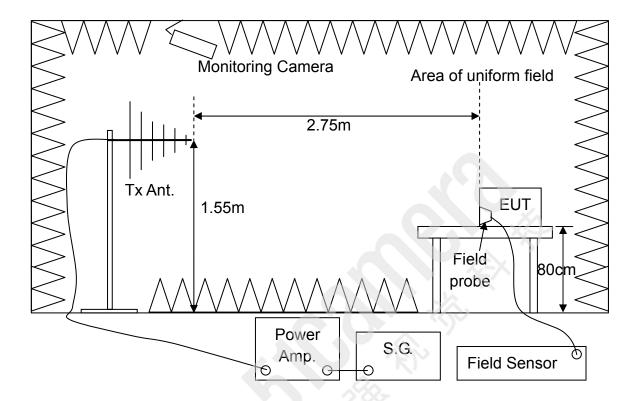
7.4 Test Procedures

- a. The EUT was set up per the test configuration figured in the next section of this chapter to simulate the typical usage per the user's manual.
- b. If the EUT is tabletop equipment, it was placed on a wooden table with a height of 0.8 meters and 2.75 meters away from the transmitting antenna in the fully anechoic chamber.
- c. If the EUT is floor-standing equipment, it was placed on a non-conducted support with a height of 0.1 meters and 2.75 meters away from the transmitting antenna in the fully anechoic chamber. Also if the floor-standing equipment which is capable of being stood on a non-conducting 0.8m high platform may be so arranged.
- d. All EUT's individual faces shall be fully enclosed by the "uniform area" and its wires shall be arranged parallel to the uniform area of the field.
- e. Before testing the EUT, the intensity of the established field strength is checked by placing the field sensor at a calibration grid point to give the calibrated field strength to measure the EUT.
- f. After the calibration has been verified, the test field can be generated using the values obtained from the calibration.
- g. Perform the test with the specified immunity level in the test frequency range and with the specified modulation type.
- h. The transmitting antenna is normally facing each of the four sides of the EUT with two polarizations (Vertical and Horizontal) to perform the test.
- i. The dwell time at each frequency shall be not less than the time necessary for the EUT to be exercised and be able to respond.
- j. The sensitive frequencies of EUT shall be analyzed separately, if any.
- k. Record the performance of the EUT.

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7.5 Test Configurations



7.6 Photographs of the Test Configurations

Please refer to the Attachment 1 of the present report.

7.7 Test Results

Test Mode : Normal

Side of the EUT	Polarization	Perfo	Performance		
Side of the Eof	Polarization	Required	Observation	(Pass/Fail)	
Front	Н	А	A(1)	Pass	
Tront	V	А	A(1)	Pass	
Left	Н	А	A(1)	Pass	
	V	Α	A(1)	Pass	
Back	Н	Α	A(1)	Pass	
Baok	V	А	A(1)	Pass	
Right	Н	Α	A(1)	Pass	
ragin	V	Α	A(1)	Pass	

Observation of Performance during Test

(1) Normal operation condition specified by manufacturer during the test.

8. Electrical fast transient / burst (EFT) Immunity Test

Test Result : PASS

8.1 Specifications of Immunity Test Requirement

Product (Generic) Standard : EN 55024:2010

Basic Standard : EN 61000-4-4:2012

Required Performance : B

Test Level : 2

Voltage Peak : ☑ ±1kV (on power supply port)

☐ ±0.5kV (on I/O signal, data and control port)

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Impulse Frequency : 5kHz

Wave Shape of the Pulse (T_r/T_h) : 5ns / 50ns

Burst Duration : 15ms

Burst Period : 300ms

Time Duration : 1 min

Test Voltage : 230V/50Hz to the connected PC

Tester : Eddie

Ambient Temperature : 24°C

Relative Humidity : 32%

Atmospheric Pressure : 1025mbar

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8.2 Description of Performance Criteria

Criteria A: normal performance within levels specified by the manufacturer,

requestor or purchaser;

Criteria B: temporary loss of function or degradation of performance which ceases

after the disturbance ceases, and from which the EUT recovers its

normal performance, without operator intervention;

Criteria C: temporary loss of function or degradation of performance, the correction

of which requires operator intervention;

Criteria D: loss of function or degradation of performance which is not recoverable,

owing to damage to hardware or software, or loss of data.

8.3 Test Instruments

Test Site and Equipment	Manufacturer	Model No./ Serial No.	Last Calibration Date	Calibration Due Date	
EFT/Burst Simulator	EMC PARTNER	TRA2000IN6/ 870	April 2, 2013	April 2, 2014	
Coupling Clamp	EMC PARTNER	CN-EFT1000/ 532	Oct. 28, 2013	Oct. 28, 2014	
Test Software	EMC PARTNER	TEMA/ Ver. 2.05	NCR	NCR	
TR7 shielded room	ETS. LINDGREN	TR7/ 15353-D	NCR	NCR	

Note:

The calibrations are traceable to NML/ROC.

2. NCR: No Calibration Required.

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8.4 Test Procedures

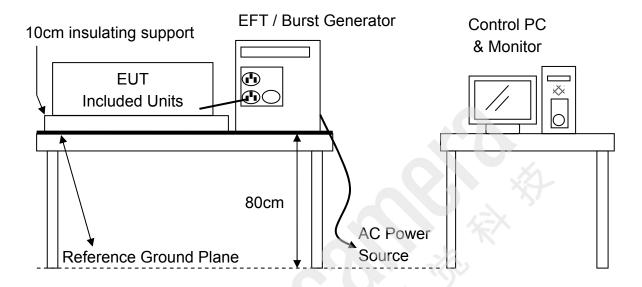
- a. The EUT was set up per the test configuration figured in the next section of this chapter to simulate the typical usage per the user's manual.
- b. If the EUT is tabletop equipment, it was placed on a non-conducted support with a height 0.1 meters above the ground reference plane. Also the ground reference plane is placed on a wooden table with a height of 0.8 meters in the shielded room. The ground reference plane shall project beyond the EUT by at least 0.1m on all sides.
- c. If the EUT is floor-standing equipment, it was placed on a non-conducted support with a height of 0.1 meters above the ground reference plane in the shielded room. The ground reference plane shall project beyond the EUT by at least 0.1m on all sides.
- d. The test generator and the coupling/decoupling network shall be placed directly on, and bonded to, the ground reference plane.
- e. All cables to the EUT shall be placed on the insulation support 0.1 m above the ground reference plane. Cables not subject to electrical fast transients shall be routed as far as possible from the cable under test to minimize the coupling between the cables.
- f. Keep the EUT 0.5m away from all other conductive structures, except the ground reference plane beneath the EUT as the minimum distance. Also if any, the minimum distance between the coupling clamp and all other conductive structures, except the ground reference plane beneath the coupling clamp and EUT shall be 0.5m.
- g. Keep the length of the power and signal lines, if required, between the coupling device and the EUT to be 0.5m. If a non-detachable supply cable more than 0.5m long, the excess length of this cable shall be folded to avoid a flat coil and situated at a distance of 0,1 m above the ground reference plane.
- h. Connect the EUT's power source to the appropriate power through the coupling devices and perform the specified test level.
- i. If any, connect all the I/O signal, data and control lines between EUT and accessories/support units through the coupling devices and perform the specified test level.
- j. Record the performance of the EUT.

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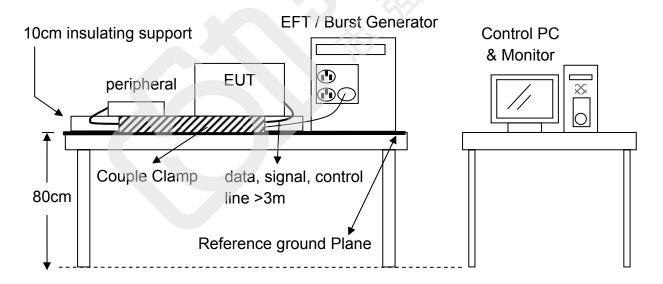
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8.5 Test Configurations

Power supply port Test



I/O signal, data and control port Test (if any)



8.6 Photographs of the Test Configurations

Please refer to the Attachment 1 of the present report.

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8.7 Test Results

Test Mode : Normal

Injected Line	Voltage Peak	Injected	Performance Required Observation		Result
	(kV)	Method			(Pass/Fail)
L1 - L2 - PE	±1.0	Direct	В	A(1)	Pass

Observation of Performance during Test

(1) Normal operation condition specified by manufacturer during the test.

9. Surge Immunity Test

Test Result : PASS

9.1 Specifications of Immunity Test Requirement

Product (Generic) Standard : EN 55024:2010

Basic Standard : EN 61000-4-5:2006

Required Performance : B

Test Level : ☑ 2 (line to line on power supply port)

☑ 3 (line to earth (ground) on power supply port)

☐ 2 (on I/O signal, data and control port)

Open-circuit Test Voltage : $\boxtimes \pm 0.5$ kV, ± 1 kV (line to line on power supply port)

±0.5kV, ±1kV, ±2kV (line to earth (ground) on

power supply port)

□ ±0.5kV, ±1kV

(on I/O signal, data and control port)

CW Waveform (T_r/T_h) : 1.2 / 50µs (open-circuit voltage)

8 / 20µs (short-circuit current)

Phase Angel / Reference : 0°, 90°, 180°, 270° / L1

Repetition Rate : 1/min. maximum

Number of Test : at least 5 positive and 5 negative at selected points

Test Voltage : 230V/50Hz to the connected PC

Tester : Eddie

Ambient Temperature : 24°C

Relative Humidity : 32%

Atmospheric Pressure : 1025mbar

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9.2 Description of Performance Criteria

Criteria A: normal performance within levels specified by the manufacturer,

requestor or purchaser;

Criteria B: temporary loss of function or degradation of performance which ceases

after the disturbance ceases, and from which the EUT recovers its

normal performance, without operator intervention;

Criteria C: temporary loss of function or degradation of performance, the correction

of which requires operator intervention;

Criteria D: loss of function or degradation of performance which is not recoverable,

owing to damage to hardware or software, or loss of data.

9.3 Test Instruments

Test Site and Equipment	Manufacturer	Model No./ Serial No.	Last Calibration Date	Calibration Due Date	
Surge Simulator	EMC PARTNER	TRA2000IN6/ 870	April 2, 2013	April 2, 2014	
Telecom Coupler	KeyTek	CM-TELCD/ 0103215	June 27, 2013	June 27, 2015	
Test Software	EMC PARTNER	TEMA/ Ver. 2.05	NCR	NCR	
TR7 shielded room	ETS. LINDGREN	TR7/ 15353-D	NCR	NCR	

Note:

The calibrations are traceable to NML/ROC.

NCR : No Calibration Required.

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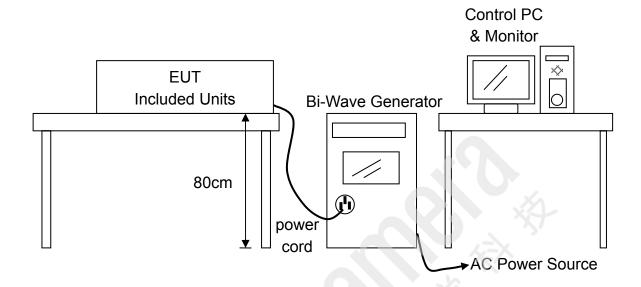
9.4 Test Procedures

- a. The EUT was set up per the test configuration figured in the next section of this chapter to simulate the typical usage per the user's manual.
- b. If the EUT is tabletop equipment, it was placed on a wooden table with a height of 0.8 meters in the shielded room.
- c. If the EUT is floor-standing equipment, it was placed on a non-conducted support with a height of 0.1 meters above the ground reference plane in the shielded room.
- d. For the surge test applied to EUT's power supply and unshielded unsymmetrical interconnection lines, if required, the capacitive coupling network are used.
- e. If any, the surge test applied to the unshielded symmetrically interconnection lines of EUT, the gas arrestors coupling network are used.
- f. Keep the interconnection line, if required, or power cord between the EUT or its power source and the coupling / decoupling network to be 2m in length (or shorter).
- g. The surges have to be applied synchronized to the voltage phase at the zero-crossing and the peak value of the a.c. voltage wave (positive and negative).
- h. All lower levels including the selected test level shall be satisfied and the test voltage has to be increased by steps up to the specified test level.
- Connect the EUT's power source to the appropriate power through the coupling devices and perform the specified test level.
- j. If any, connect all the interconnection lines between EUT and accessories/support units through the coupling devices and perform the specified test level.
- k. Record the performance of the EUT.

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9.5 Test Configurations



9.6 Photographs of the Test Configurations

Please refer to the Attachment 1 of the present report.

9.7 Test Results

Test Mode : Normal

	Open-circuit	Performance			Result		
Coupled Line	Test Voltage	Doguirod	Observation			Observation	(Pass/Fail)
	(kV)	Required	0°	90°	180°	270°	(Fass/Fall)
L1 - PE	±0.5	В	A(1)	A(1)	A(1)	A(1)	Pass
L2 - PE	±0.5	В	A(1)	A(1)	A(1)	A(1)	Pass
L1 - L2	±0.5	В	A(1)	A(1)	A(1)	A(1)	Pass
L1 - PE	±1	В	A(1)	A(1)	A(1)	A(1)	Pass
L2 - PE	±1	В	A(1)	A(1)	A(1)	A(1)	Pass
L1 - L2	±1	В	A(1)	A(1)	A(1)	A(1)	Pass
L1 - PE	±2	В	A(1)	A(1)	A(1)	A(1)	Pass
L2 - PE	±2	В	A(1)	A(1)	A(1)	A(1)	Pass

Observation of Performance during Test

(1) Normal operation condition specified by manufacturer during the test.

10. Conducted disturbances (CS) Immunity Test

Test Result : PASS

10.1 Specifications of Immunity Test Requirement

Product (Generic) Standard : EN 55024:2010

Basic Standard : EN 61000-4-6:2009

Required Performance : A

Test Level : 2

Voltage Level(e.m.f.) : 3V (e.m.f.)

Test Frequency Range : 150kHz ~ 80MHz

Frequency Step : 1% of the momentary frequency

Dwell Time : Minimum 3 sec. per frequency

Modulation : 1kHz Sine Wave with 80% Amplitude Modulation

Coupling Devices : ☑ CDN-M3 (on power supply port)

☐ CDN-T2 (on RJ-11 port)

☐ CDN-T4 (on LAN port)

☐ CDN-T8 (on LAN port)

☐ EM Clamp (on I/O signal, data and control port)

Test Voltage : 230V/50Hz to the power adapter

Tester : Eddie

Ambient Temperature : 23°C

Relative Humidity : 31%

Atmospheric Pressure : 1025mbar

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10.2 Description of Performance Criteria

Criteria A: normal performance within levels specified by the manufacturer,

requestor or purchaser;

Criteria B: temporary loss of function or degradation of performance which ceases

after the disturbance ceases, and from which the EUT recovers its

normal performance, without operator intervention;

Criteria C: temporary loss of function or degradation of performance, the correction

of which requires operator intervention;

Criteria D: loss of function or degradation of performance which is not recoverable,

owing to damage to hardware or software, or loss of data.

10.3 Test Instruments

Test Site and Equipment	Manufacturer	Model No./ Serial No.	Last Calibration Date	Calibration Due Date
Signal Generator	R&S	SML03/ 101676	July 15, 2013	July 15, 2014
Dual Directional Coupler	AR	DC2600/ 28834	Jan. 3, 2013	Jan. 3, 2014
Power Amplifier	AR	75A250/ 28845	NCR	NCR
CDN		□ FCC-801-M2-16A/ 2032	Jan. 14, 2013	Jan. 14, 2014
	FCC	FCC-801-M3-16A/ 2060	Jan. 14, 2013	Jan. 14, 2014
		□ FCC-801-M5-16A/ 2020	Jan. 14, 2013	Jan. 14, 2014
	FCC	□ FCC-801-T2/ 2032	Sept. 9, 2013	Sept. 9, 2014
		FCC-801-T4-RJ45/ 08031	Sept. 13, 2013	Sept. 13, 2014
		□ NCDN-T8-RJ45/ 06016	March 16, 2013	March 16, 2014
EM CLAMP	FCC	FCC-203I-23MM/ 107	Jan. 4, 2013	Jan. 4, 2014
Dual Channel Power Meter	R&S	NRVD/ 100499	Jan. 4, 2013	Jan. 4, 2014
Power Sensor	R&S	URV5-Z2/ 835640/013	Jan. 4, 2013	Jan. 4, 2014
	R&S	URV5-Z2/ 100731	Jan. 4, 2013	Jan. 4, 2014
Test Software	Audix	i2/ V5.10.5	NCR	NCR
AR shielded room	ETS. LINDGREN	AR/ 15353-J	NCR	NCR

Note:

- 1. The calibrations are traceable to NML/ROC.
- 2. NCR: No Calibration Required.

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10.4 Test Procedures

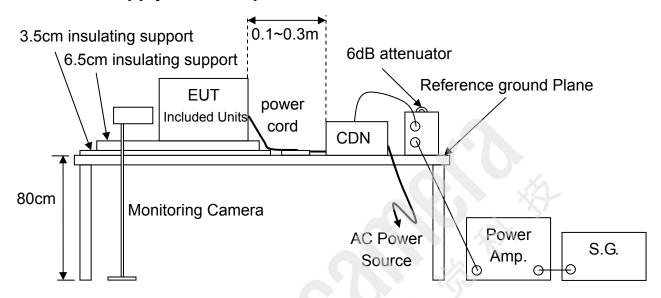
- a. The EUT was set up per the test configuration figured in the next section of this chapter to simulate the typical usage per the user's manual.
- b. If the EUT is tabletop equipment, it was placed on a non-conducted support with a height 0.1 meters above the ground reference plane. Also the ground reference plane is placed on a wooden table with a height of 0.8 meters in the shielded room.
- c. If the EUT is floor-standing equipment, it was placed on a non-conducted support with a height of 0.1 meters above the ground reference plane in the shielded room.
- d. Decide the injection methods and test points according to the relative standard.
- e. All relevant cables shall be provide with the appropriate coupling and decoupling devices at a distance between 0.1m and 0.3m from the projected geometry of the EUT on the ground reference plane.
- f. All cables connected to each Auxiliary Equipment (AE), other than those being connected to the EUT, shall not be bundled nor wrapped and shall be kept between 30mm and 50mm above the ground reference plane.
- g. The test shall be performed with the test generator connected to each of the coupling and decoupling devices in turn while the other non-excited RF input ports of the coupling devices are terminated by a 50Ω load resistor.
- h. Perform the test with the specified immunity level in the test frequency range and with the specified modulation type.
- i. The dwell time at each frequency shall be not less than the time necessary for the EUT to be exercised and be able to respond.
- j. The sensitive frequencies of EUT and harmonics or frequencies of dominant interest shall be analyzed separately, if any.
- k. Record the performance of the EUT.

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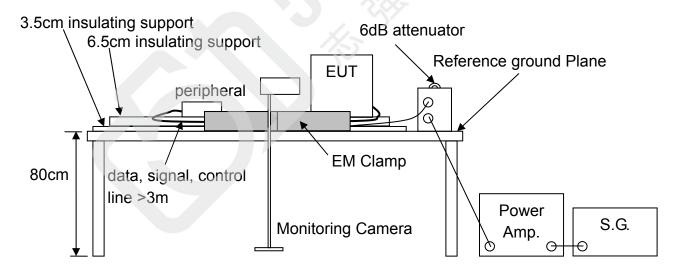
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10.5 Test Configurations

Power supply and LAN port Test



I/O signal, data and control port Test (if any)



10.6 Photographs of the Test Configurations

Please refer to the Attachment 1 of the present report.

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10.7 Test Results

Test Mode : Normal

Injected Line	Coupling Devices	Performance		Result
injected Line	Coupling Devices	Required Observation		(Pass/Fail)
Power Lines	CDN-M3	Α	A(1)	Pass

Observation of Performance during Test

(1) Normal operation condition specified by manufacturer during the test.

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11. Power frequency magnetic field (PFM) Immunity Test

Test Result : PASS

11.1 Specifications of Immunity Test Requirement

Product (Generic) Standard : EN 55024:2010

Basic Standard : EN 61000-4-8:2010

Required Performance : A

Test Level : 1

Magnetic Field Strength : 1 A/m

Power Frequency : 50 Hz

Test Duration : 1 min.

Magnetic Field Orientation : X, Y, Z-axis

Test Voltage : 230V/50Hz to the connected PC

Tester : Kent

Environment Magnetic Field: 0.01 A/m (< 0.1 A/m (20dB below the test field))

Ambient Temperature : 20°C

Relative Humidity : 60%

Atmospheric Pressure : 1019mbar

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11.2 Description of Performance Criteria

Criteria A: normal performance within levels specified by the manufacturer,

requestor or purchaser;

Criteria B: temporary loss of function or degradation of performance which ceases

after the disturbance ceases, and from which the EUT recovers its

normal performance, without operator intervention;

Criteria C: temporary loss of function or degradation of performance, the correction

of which requires operator intervention;

Criteria D: loss of function or degradation of performance which is not recoverable,

owing to damage to hardware or software, or loss of data.

11.3 Test Instruments

Test Site and Equipment	Manufacturer	Model No./ Serial No.	Last Calibration Date	Calibration Due Date
Current Source	FCC	F-1000-4-8-125A/ 1008	June 28, 2013	June 28, 2014
Coil	FCC	F-1000-4-8-1M/ 1007	June 28, 2013	June 28, 2014
Low Frequency Gauss Meter	CHAUVIN ARNOUX	C.A40/ 150361	July 19, 2013	July 19, 2014
TR12 Plane Grounding Site	CRC	TR12	NCR	NCR

Note:

1. The calibrations are traceable to NML/ROC.

2. NCR: No Calibration Required.

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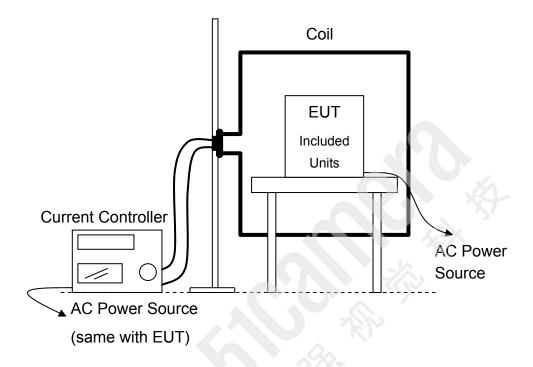
11.4 Test Procedures

- a. The EUT was set up per the test configuration figured in the next section of this chapter to simulate the typical usage per the user's manual.
- b. If the EUT is tabletop equipment, it was placed on a wooden table with a height 0.8 meters.
- c. If the EUT is floor-standing equipment, it was placed on a non-conducted support with a height of 0.1 meters above the ground reference plane (minimum size is 1m×1m) in the shielded room.
- d. For the tabletop equipment, the induction coil with a square form in 1m side (or diameter) is used and shall enclose the EUT placed at its center. For the floorstanding equipment, the induction coil shall be able to envelop the EUT and made of conductors of relatively small cross-section.
- e. The dimensions of induction coil shall be able to keep the magnetic fields over the whole volume of the EUT with an acceptable variation of ± 3 dB.
- f. The test generator shall be placed at less than 3m distance from the induction coil.
- g. Keep all cables of EUT to be exposed to the magnetic field for 1m of their length.
- h. Before the test, maintain the electromagnetic field value of the test environment to be at least 20dB lower than the selected test level. Then tune up the currents of the test generator and use the Guass Meter to calibrate the specified test level at the center of the induction coil.
- i. Perform the test with the specified magnetic field by rotating the induction coil to three different orientations to generate X, Y and Z directed magnetic field sequentially.
- Record the performance of the EUT.

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11.5 Test Configurations



11.6 Photographs of the Test Configurations

Please refer to the Attachment 1 of the present report.

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11.7 Test Results

Test Mode : Normal

Magnetic Field	Magnetic Field	Frequency	Performance		Result
Orientation	(A/m)	(Hz)	Required	Observation	(Pass/Fail)
X-axis	1	50	Α	A(1)	Pass
Y-axis	1	50	Α	A(1)	Pass
Z-axis	1	50	Α	A(1)	Pass

Observation of Performance during Test

(1) Normal operation condition specified by manufacturer during the test.

12. Voltage dips, short interruptions Immunity Test

Test Result : PASS

12.1 Specifications of Immunity Test Requirement

Product (Generic) Standard : EN 55024:2010

Basic Standard : EN 61000-4-11:2004

Required Performance : ☑ B for 0% residual voltage dips with 0.5 cycle

and Test Level
☑ C for 70% residual voltage dips with 25

cycles

☐ C for 40% residual voltage dips

☑ C for 0% residual voltage interruptions

with 250 cycles

Basis Test Voltage Level (U_T) : 230V/50Hz to the connected PC

Test Duration: Maximum 3 dips/interruptions with a sequence

Time interval : 10s minimum between each test event

Phase Angle of Abrupt Changes: 0°

Tester : Eddie
Ambient Temperature : 24°C
Relative Humidity : 32%

Atmospheric Pressure : 1025mbar

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12.2 Description of Performance Criteria

Criteria A: normal performance within levels specified by the manufacturer,

requestor or purchaser;

Criteria B: temporary loss of function or degradation of performance which ceases

after the disturbance ceases, and from which the EUT recovers its

normal performance, without operator intervention;

Criteria C: temporary loss of function or degradation of performance, the correction

of which requires operator intervention;

Criteria D: loss of function or degradation of performance which is not recoverable,

owing to damage to hardware or software, or loss of data.

12.3 Test Instruments

Test Site and	Manufacturer	Model No./	Last	Calibration	
Equipment		Serial No.	Calibration Date	Due Date	
Voltage DIP	EMC PARTNER	TRA2000IN6/	April 2, 2013	April 2, 2014	
Tester	EWIC FARTNER	870	April 2, 2013		
Test Software	EMC PARTNER	TEMA/	NCR	NCR	
lest Software	LIVIC FAITTNEIX	Ver. 1.86	NOIX	NOR	
TR7	ETS.	TR7/	NCR	NCR	
shielded room	LINDGREN	15353-D	NOR		

Note:

1. The calibrations are traceable to NML/ROC.

2. NCR: No Calibration Required.

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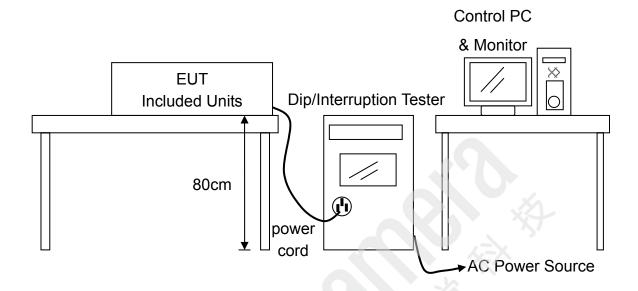
12.4 Test Procedures

- a. The EUT was set up per the test configuration figured in the next section of this chapter to simulate the typical usage per the user's manual.
- b. If the EUT is tabletop equipment, it was placed on a wooden table with a height 0.8 meters above the ground reference plane in the shielded room.
- c. If the EUT is floor-standing equipment, it was placed on a non-conducted support with a height of 0.1 meters above the ground reference plane in the shielded room.
- d. The test shall be performed with the EUT connected to the test Generator with the shortest power supply cable as specified by the manufacturer.
- e. If any, tests on the three-phase EUT are accomplished by using three sets of equipment mutually synchronized.
- f. During the tests, the main voltage for testing is monitored within an accuracy of 2% and the zero crossing control of the generators must have an accuracy of $\pm 10^{\circ}$.
- g. The EUT shall be tested for each selected combination of test level and duration with a sequence of three dips/interruptions with intervals of 10 sec. minimum (between each test event). Each representative mode of operation shall be test.
- h. Abrupt changes in supply voltage shall occur at zero crossings of the voltage and additional angles preferably selected from 0°, 45°, 90°, 135°, 180°, 225°, 270°, 315° on each phase.
- i. Connect the EUT's power source to the appropriate power through the test generator and perform the specified test level.
- j. Record the performance of the EUT.

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12.5 Test Configurations



12.6 Photographs of the Test Configurations

Please refer to the Attachment 1 of the present report.

12.7 Test Results

Test Mode : Normal

Voltage Dips Test

Test level	Reduction Voltage (%)	Duration (cycle)	Perfo	Result	
(% residual voltage)			Required	Observation	
0	>95	0.5	В	A(1)	Pass
70	30	25	С	A(1)	Pass

Voltage Interruption Test

Test level	Reduction Duration		Perfo	Result	
(% residual voltage)	Voltage	(cycle)	Required	Observation	
0	>95	250	С	C(2)	Pass

Observation of Performance during Test

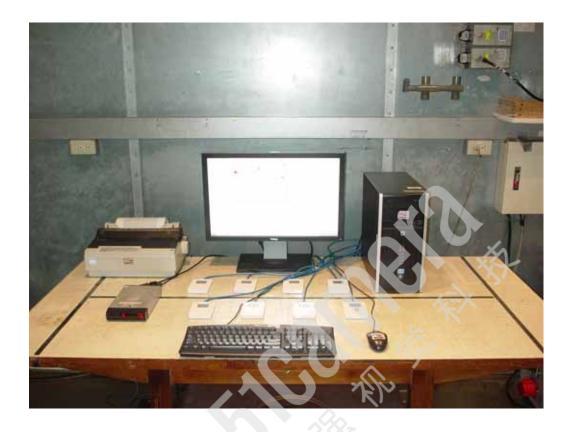
- (1) Normal operation condition specified by manufacturer during the test.
- (2) The EUT shuts down with PC while test is performing, it can be restarted manually after the test.

Attachment 1 Photographs of the Test Configurations

Contents

1.	Conducted Emission Measurement	. 1
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1. Conducted Emission Measurement





Radiated Emission Measurement





3. Harmonic Current & Voltage Fluctuations Emission Measurement





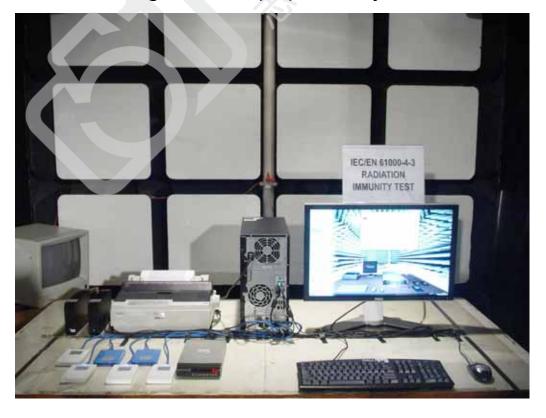
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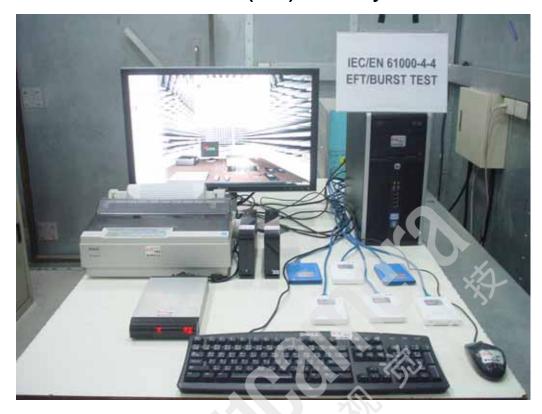
4. Electrostatic Discharge (ESD) Immunity Test



5. Radiated Electromagnetic Field (RS) Immunity Test



6. Electrical fast transient / burst (EFT) Immunity Test



7. Surge Immunity Test



8. Conducted disturbances (CS) Immunity Test



9. Power frequency magnetic field (PFM) Immunity Test



10. Voltage dips, short interruptions Immunity Test



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Attachment 2 **Photographs of EUT**







